

Notice of References Cited	Application/Control No. 10/822,960	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Andy Huynh	Art Unit 2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,329,826	12-2001	Shinada et al.	324/751
*	B	US-6,355,516	03-2002	Kim et al.	438/240
*	C	US-6,410,927	06-2002	Pike, Christopher Lee	250/491.1
*	D	US-6,512,227	01-2003	Iwabuchi et al.	250/310
*	E	US-6,841,008	01-2005	Branco et al.	134/26
*	F	US-6,900,135	05-2005	Somekh et al.	438/704
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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